

Search Notes

Application/Control No.

10/643,052

Examiner

Drew E. Becker

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner
Search updated		2-27-07	DEB

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR